


<b>Search Notes</b>  	<b>Application/Control No.</b>  10586825	<b>Applicant(s)/Patent Under Reexamination</b>  PARK ET AL.
	<b>Examiner</b>  QUN SHEN	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
370	315	2/2/2010	qs
455	combined with text	2/2/2010	qs
370	combined with text	2/2/2010	qs

SEARCH NOTES			
Search Notes		Date	Examiner
Text search with EAST		2/2/2010	qs
international search report		2/2/2010	qs
inventor search		2/2/2010	qs

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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